Dual Self-Protected Low-Side Driver with Temperature and Current Limit

NCV8402D, NCV8402AD

NCV8402D/AD is a dual protected Low−Side Smart Discrete device. The protection features include overcurrent, overtemperature, ESD and integrated Drain−to−Gate clamping for overvoltage protection. This device offers protection and is suitable for harsh automotive environments.

Features
- Short−Circuit Protection
- Thermal Shutdown with Automatic Restart
- Overvoltage Protection
- Integrated Clamp for Inductive Switching
- ESD Protection
- dV/dt Robustness
- Analog Drive Capability (Logic Level Input)
- NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC−Q101 Qualified and PPAP Capable
- These Devices are Pb−Free, Halogen Free/BFR Free and are RoHS Compliant

Typical Applications
- Switch a Variety of Resistive, Inductive and Capacitive Loads
- Can Replace Electromechanical Relays and Discrete Circuits
- Automotive / Industrial

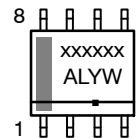| $V_{(BR)DSS}$ (Clamped)	$R_{DS(ON)}$ TYP	I_D MAX
42 V	165 mΩ @ 10 V	2.0 A*

*Max current limit value is dependent on input condition.
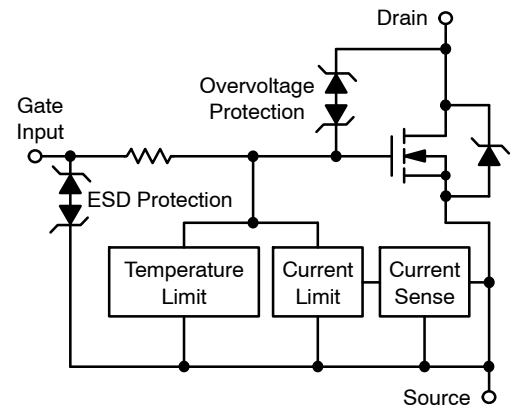
MARKING DIAGRAM

SO−8
CASE 751
STYLE 11

xxxxxx	= V8402D or 8402AD
A	= Assembly Location
L	= Wafer Lot
Y	= Year
W	= Work Week
▪	= Pb−Free Package

PIN ASSIGNMENT

Source 1 — 1 ... 8 — Drain 1
Gate 1 — — Drain 1
Source 2 — — Drain 2
Gate 2 — — Drain 2
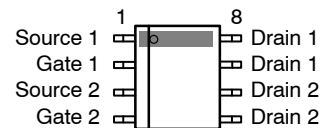
ORDERING INFORMATION

Device	Package	Shipping†
NCV8402DDR2G	SOIC−8 (Pb−Free)	2500/Tape & Reel
NCV8402ADDR2G		

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.
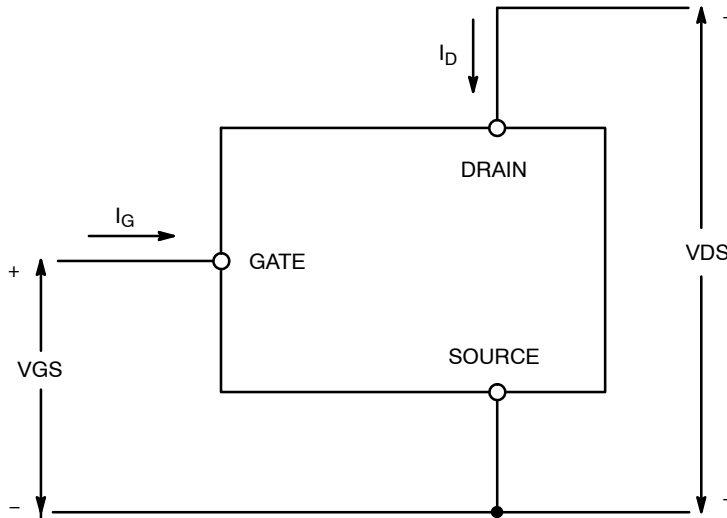
MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Rating		Symbol	Value	Unit
Drain−to−Source Voltage Internally Clamped		V_{DSS}	42	V
Drain−to−Gate Voltage Internally Clamped	(R_G = 1.0 MΩ)	V_{DGR}	42	V
Gate−to−Source Voltage		V_{GS}	± 14	V
Continuous Drain Current		I_D	Internally Limited	
Total Power Dissipation	@ T_A = 25°C (Note 1) @ T_A = 25°C (Note 2)	P_D	0.8 1.62	W
Maximum Continuous Drain, both channels on	@ T_A = 25°C (Note 1) @ T_A = 25°C (Note 2)	I_D	1.87 2.65	A
Thermal Resistance	Junction−to−Ambient Steady State (Note 1) Junction−to−Ambient Steady State (Note 2)	$R_{\theta JA}$ $R_{\theta JA}$	157 77	°C/W
Single Pulse Drain−to−Source Avalanche Energy (V_{DD} = 32 V, V_G = 5.0 V, I_{PK} = 1.0 A, L = 300 mH, $R_{G(ext)}$ = 25 Ω)		E_{AS}	150	mJ
Load Dump Voltage	(V_{GS} = 0 and 10 V, R_I = 2.0 Ω, R_L = 9.0 Ω, t_d = 400 ms)	V_{LD}	55	V
Operating Junction and Storage Temperature		T_J, T_{stg}	−55 to 150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.
1. Surface−mounted onto min pad FR4 PCB, (Cu area = 40 sq. mm, 1 oz.).
2. Surface−mounted onto 1″ sq. FR4 board (Cu area = 625 sq. mm, 2 oz.).

Figure 1. Voltage and Current Convention

NCV8402D, NCV8402AD

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Parameter	Test Condition	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
Drain−to−Source Breakdown Voltage (Note 3)	V_{GS} = 0 V, I_D = 10 mA, T_J = 25°C	$V_{(BR)DSS}$	42	46	55	V
	V_{GS} = 0 V, I_D = 10 mA, T_J = 150°C (Note 5)		40	45	55	
Zero Gate Voltage Drain Current	V_{GS} = 0 V, V_{DS} = 32 V, T_J = 25°C	I_{DSS}		0.25	4.0	μA
	V_{GS} = 0 V, V_{DS} = 32 V, T_J = 150°C (Note 5)			1.1	20	
Gate Input Current	V_{DS} = 0 V, V_{GS} = 5.0 V	I_{GSSF}		50	100	μA
ON CHARACTERISTICS (Note 3)						
Gate Threshold Voltage	V_{GS} = V_{DS}, I_D = 150 μA	$V_{GS(th)}$	1.3	1.8	2.2	V
Gate Threshold Temperature Coefficient		$V_{GS(th)}/T_J$		4.0	6.0	−mV/°C
Static Drain−to−Source On−Resistance	V_{GS} = 10 V, I_D = 1.7 A, T_J = 25°C	$R_{DS(on)}$		165	200	mΩ
	V_{GS} = 10 V, I_D = 1.7 A, T_J = 150°C (Note 5)			305	400	
	V_{GS} = 5.0 V, I_D = 1.7 A, T_J = 25°C			195	230	
	V_{GS} = 5.0 V, I_D = 1.7 A, T_J = 150°C (Note 5)			360	460	
	V_{GS} = 5.0 V, I_D = 0.5 A, T_J = 25°C			190	230	
	V_{GS} = 5.0 V, I_D = 0.5 A, T_J = 150°C (Note 5)			350	460	
Source−Drain Forward On Voltage	V_{GS} = 0 V, I_S = 7.0 A	V_{SD}		1.0		V
SWITCHING CHARACTERISTICS (Note 5)						
Turn−On Time (10% V_{IN} to 90% I_D)		t_{on}		25	30	μs
Turn−Off Time (90% V_{IN} to 10% I_D)		t_{off}		120	200	μs
Turn−On Rise Time (10% I_D to 90% I_D)	V_{GS} = 10 V, V_{DD} = 12 V, I_D = 2.5 A, R_L = 4.7 Ω	t_{rise}		20	25	μs
Turn−Off Fall Time (90% I_D to 10% I_D)		t_{fall}		50	70	μs
Slew−Rate ON (70% V_{DS} to 50% V_{DD})		$-dV_{DS}/dt_{ON}$		0.8	1.2	V/μs
Slew−Rate OFF (50% V_{DS} to 70% V_{DD})		dV_{DS}/dt_{OFF}		0.3	0.5	
SELF PROTECTION CHARACTERISTICS (T_J = 25°C unless otherwise noted) (Note 4)						
Current Limit	V_{DS} = 10 V, V_{GS} = 5.0 V, T_J = 25°C (Note 6)	I_{LIM}	3.7	4.3	5.0	A
	V_{DS} = 10 V, V_{GS} = 5.0 V, T_J = 150°C (Notes 5, 6)		2.3	3.0	3.7	
	V_{DS} = 10 V, V_{GS} = 10 V, T_J = 25°C (Note 6)		4.2	4.8	5.4	
	V_{DS} = 10 V, V_{GS} = 10 V, T_J = 150°C (Notes 5, 6)		2.7	3.6	4.5	
Temperature Limit (Turn−off)	V_{GS} = 5.0 V (Notes 5, 6)	$T_{LIM(off)}$	150	175	200	°C
Thermal Hysteresis	V_{GS} = 5.0 V	$\Delta T_{LIM(on)}$		15		
Temperature Limit (Turn−off)	V_{GS} = 10 V (Notes 5, 6)	$T_{LIM(off)}$	150	165	185	
Thermal Hysteresis	V_{GS} = 10 V	$\Delta T_{LIM(on)}$		15		
GATE INPUT CHARACTERISTICS (Note 5)						
Device ON Gate Input Current	V_{GS} = 5 V I_D = 1.0 A	I_{GON}		50		μA
	V_{GS} = 10 V I_D = 1.0 A			400		

ELECTRICAL CHARACTERISTICS (T$_J$ = 25°C unless otherwise noted)

Parameter	Test Condition	Symbol	Min	Typ	Max	Unit
GATE INPUT CHARACTERISTICS (Note 5)						
Current Limit Gate Input Current	V$_{GS}$ = 5 V, V$_{DS}$ = 10 V	I$_{GCL}$		0.05		mA
	V$_{GS}$ = 10 V, V$_{DS}$ = 10 V			0.4		
Thermal Limit Fault Gate Input Current	V$_{GS}$ = 5 V, V$_{DS}$ = 10 V	I$_{GTL}$		0.15		mA
	V$_{GS}$ = 10 V, V$_{DS}$ = 10 V			0.7		

ESD ELECTRICAL CHARACTERISTICS (T$_J$ = 25°C unless otherwise noted) (Note 5)

Parameter	Test Condition	Symbol	Min	Typ	Max	Unit
Electro−Static Discharge Capability	Human Body Model (HBM)	ESD	4000			V
	Machine Model (MM)		400			

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
4. Fault conditions are viewed as beyond the normal operating range of the part.
5. Not subject to production testing.
6. Refer to Application Note AND8202/D for dependence of protection features on gate voltage.

NCV8402D, NCV8402AD

TYPICAL PERFORMANCE CURVES
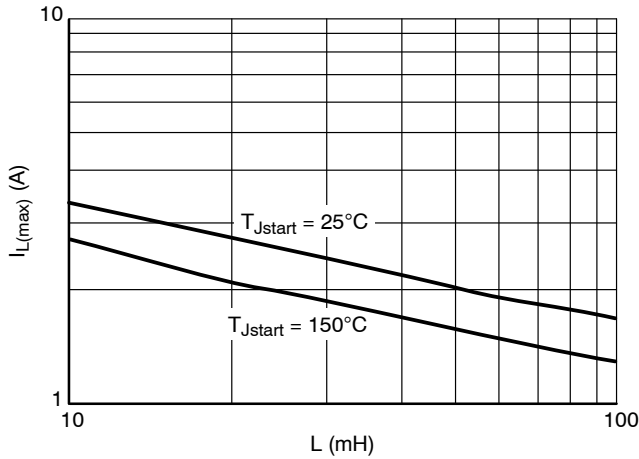
Figure 2. Single Pulse Maximum Switch−off Current vs. Load Inductance
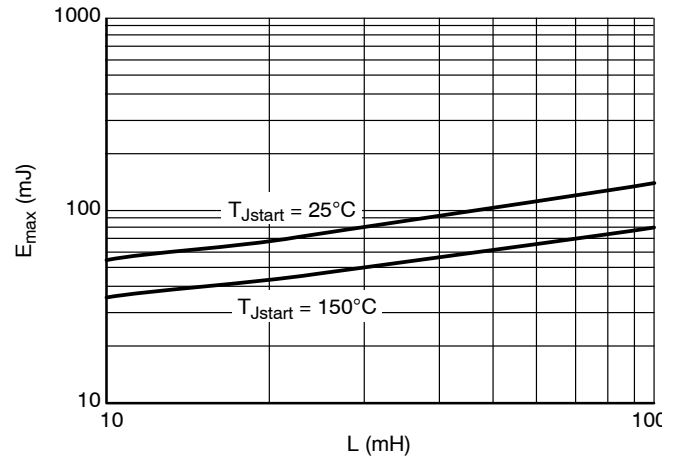
Figure 3. Single Pulse Maximum Switching Energy vs. Load Inductance
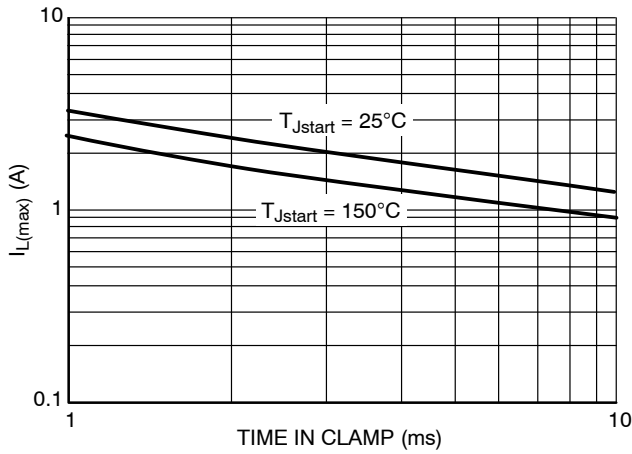
Figure 4. Single Pulse Maximum Inductive Switch−off Current vs. Time in Clamp
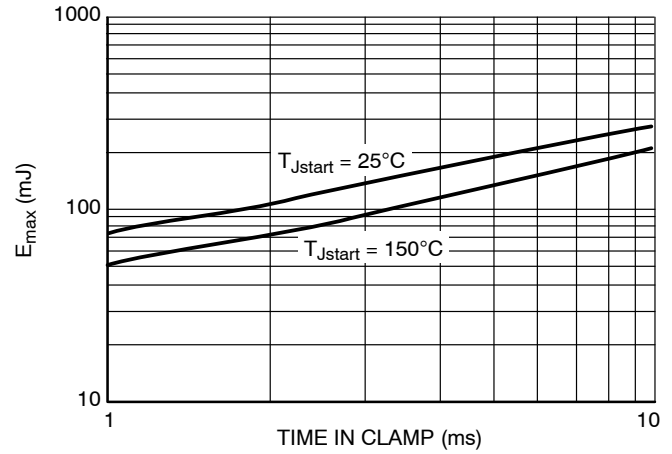
Figure 5. Single Pulse Maximum Inductive Switching Energy vs. Time in Clamp
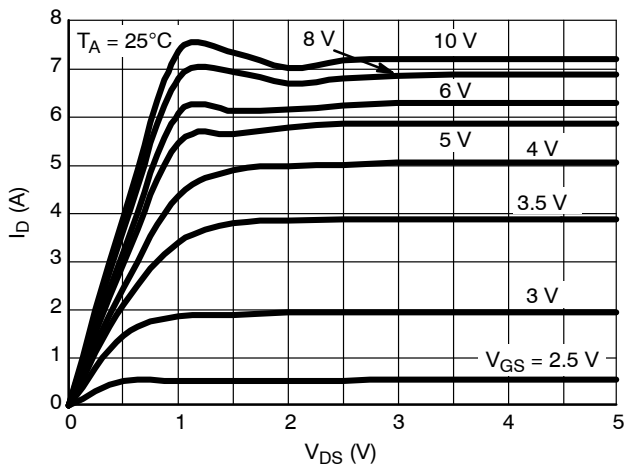
Figure 6. On−state Output Characteristics
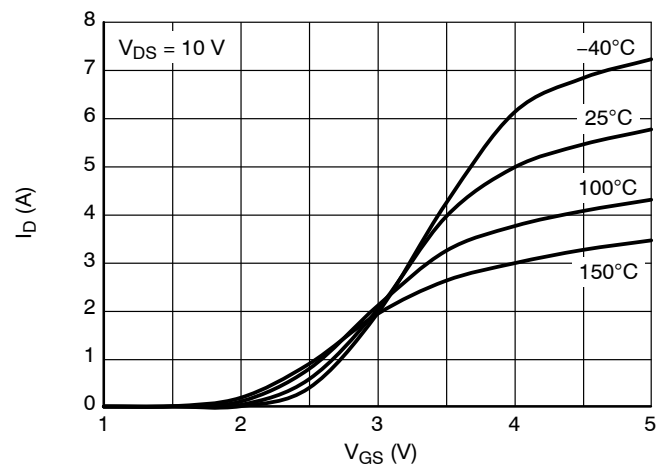
Figure 7. Transfer Characteristics

TYPICAL PERFORMANCE CURVES
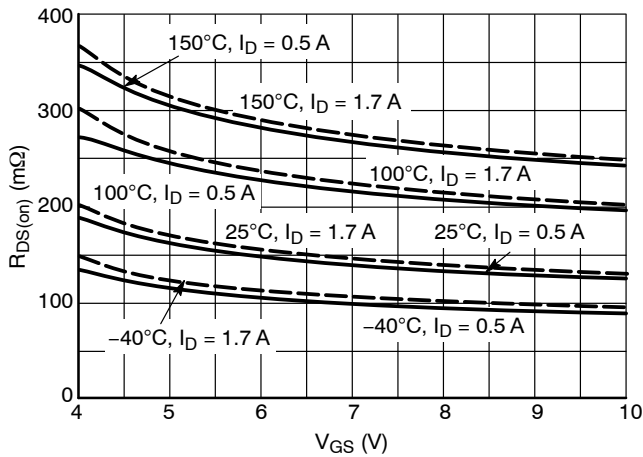
Figure 8. R$_{DS(on)}$ vs. Gate−Source Voltage
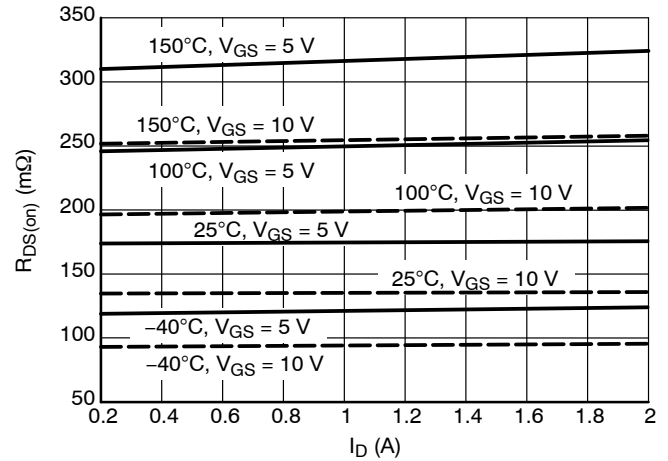
Figure 9. R$_{DS(on)}$ vs. Drain Current
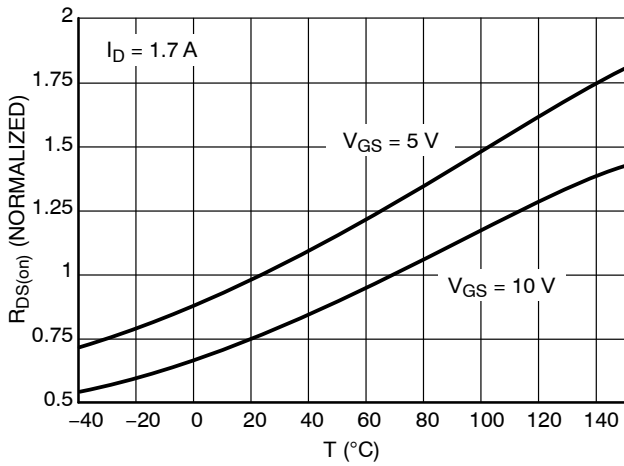
Figure 10. Normalized R$_{DS(on)}$ vs. Temperature
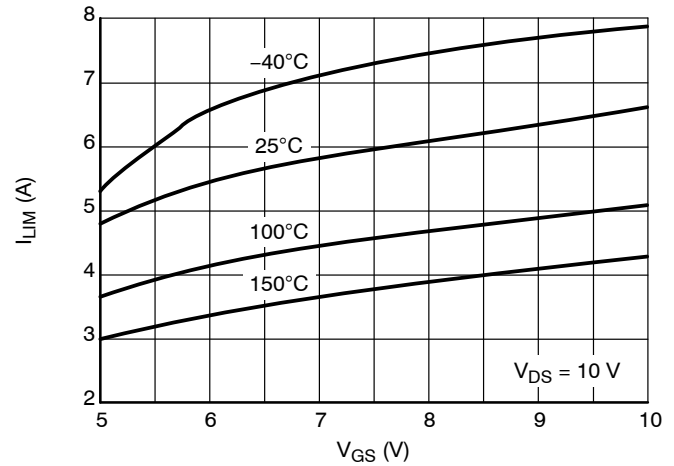
Figure 11. Current Limit vs. Gate−Source
Voltage
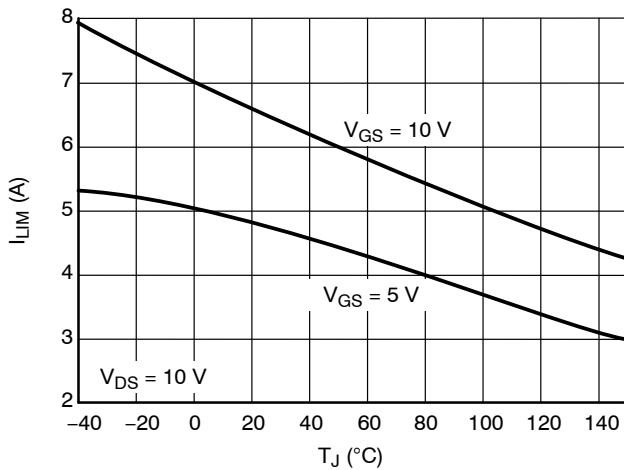
Figure 12. Current Limit vs. Junction
Temperature
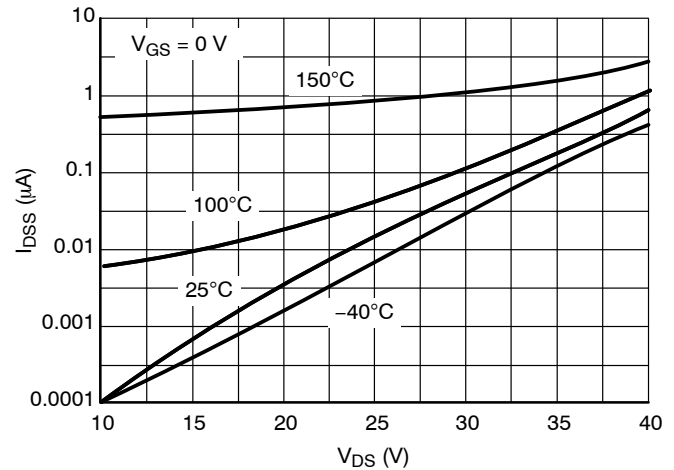
Figure 13. Drain−to−Source Leakage Current

NCV8402D, NCV8402AD

TYPICAL PERFORMANCE CURVES
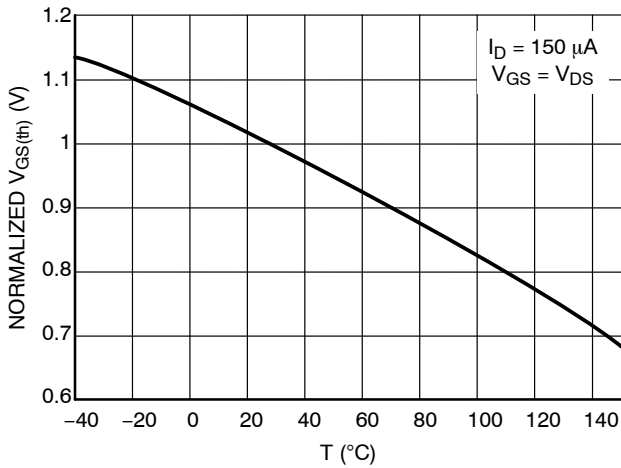
Figure 14. Normalized Threshold Voltage vs. Temperature
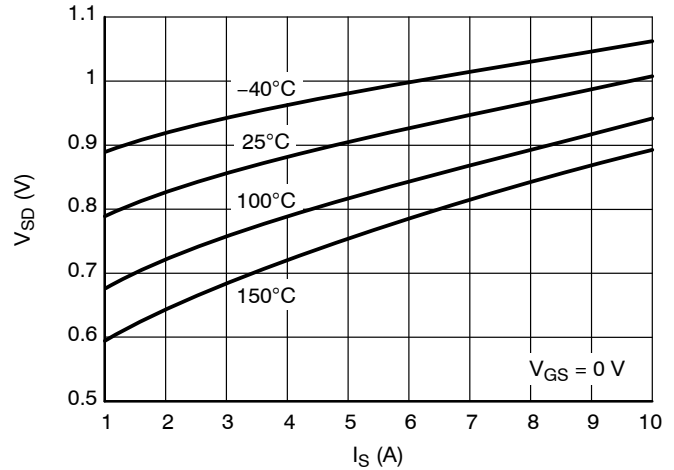
Figure 15. Source−Drain Diode Forward Characteristics
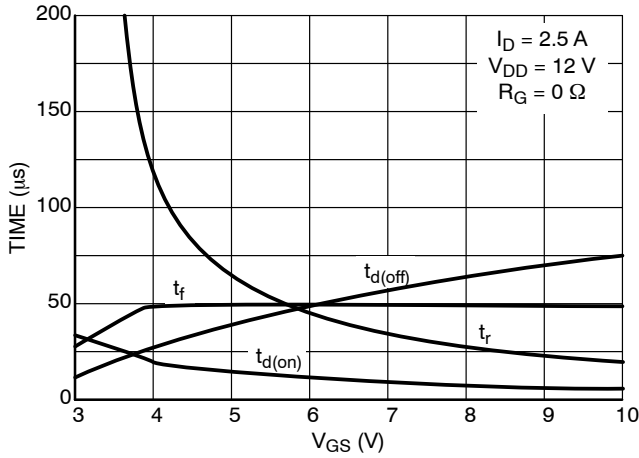
Figure 16. Resistive Load Switching Time vs. Gate−Source Voltage
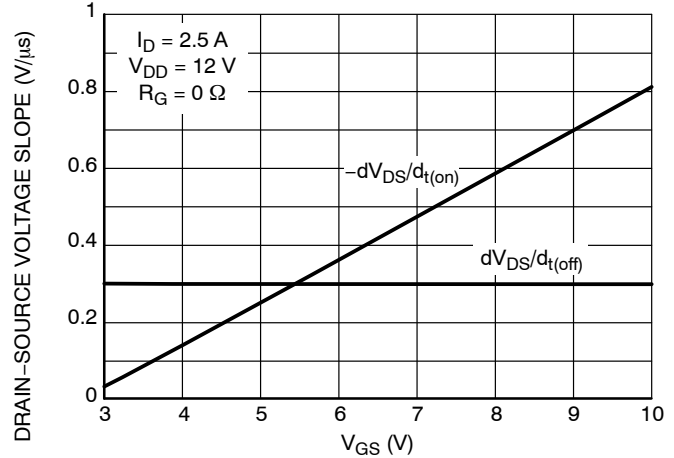
Figure 17. Resistive Load Switching Drain−Source Voltage Slope vs. Gate−Source Voltage
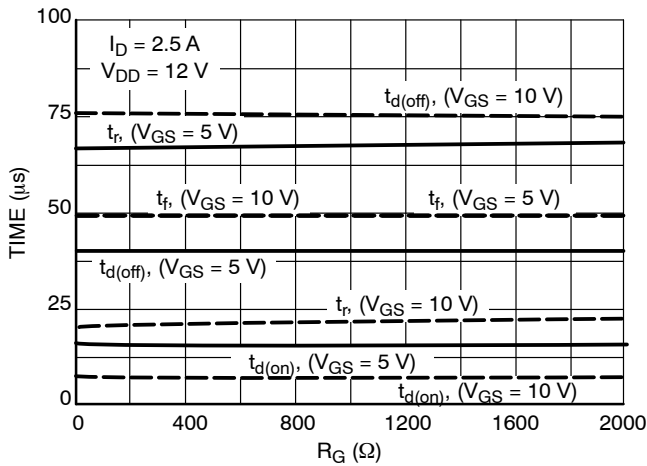
Figure 18. Resistive Load Switching Time vs. Gate Resistance
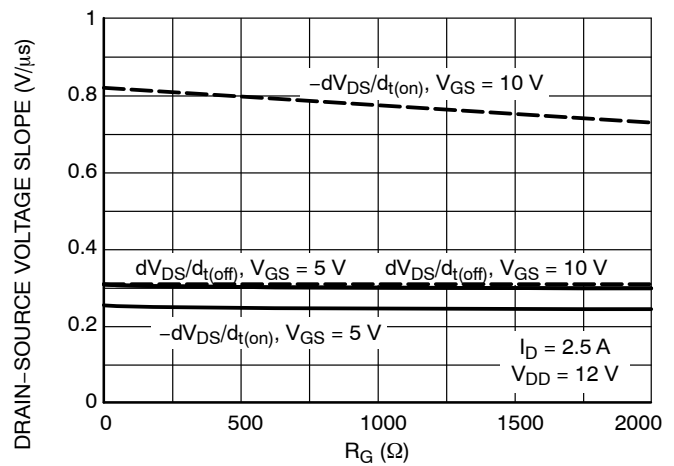
Figure 19. Drain−Source Voltage Slope during Turn On and Turn Off vs. Gate Resistance

TYPICAL PERFORMANCE CURVES
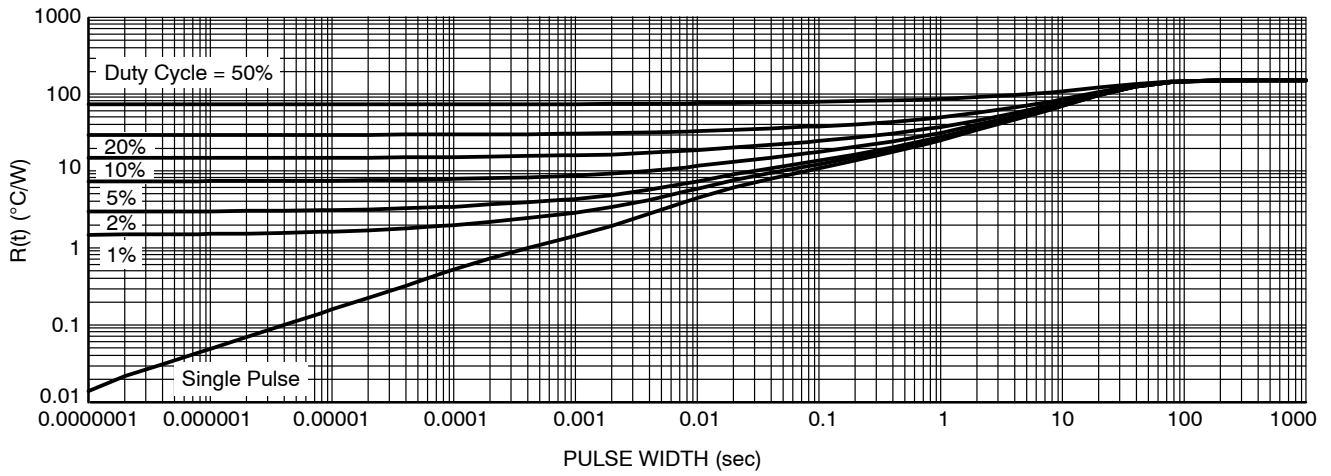
Figure 20. Transient Thermal Resistance

TEST CIRCUITS AND WAVEFORMS
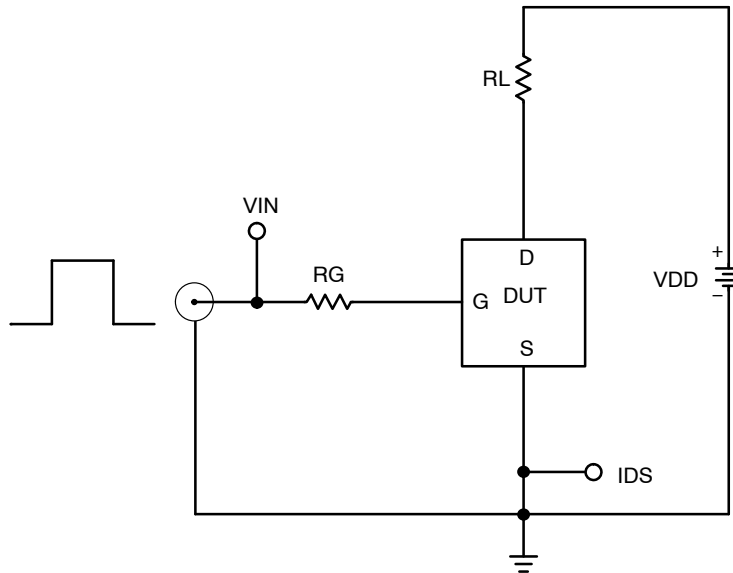
Figure 21. Resistive Load Switching Test Circuit
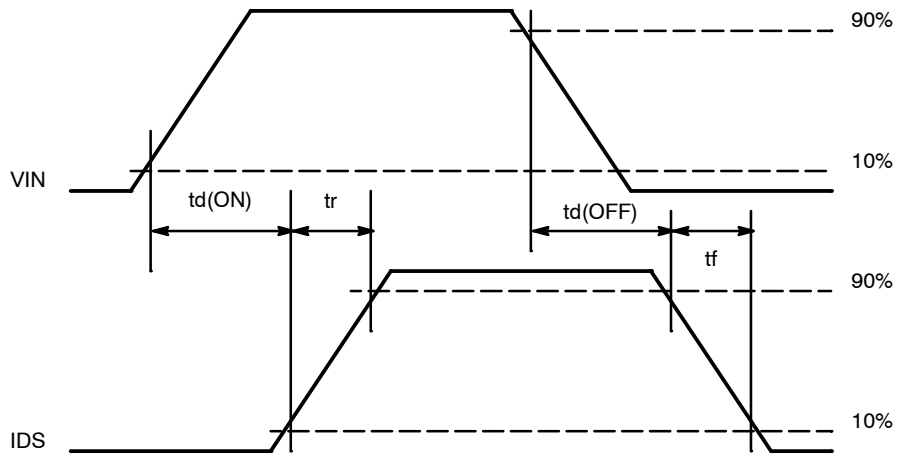
Figure 22. Resistive Load Switching Waveforms

TEST CIRCUITS AND WAVEFORMS
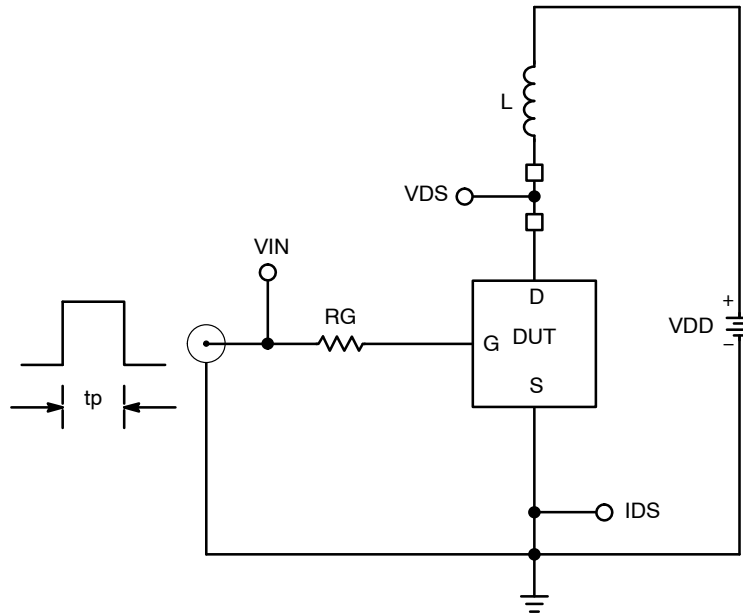
Figure 23. Inductive Load Switching Test Circuit
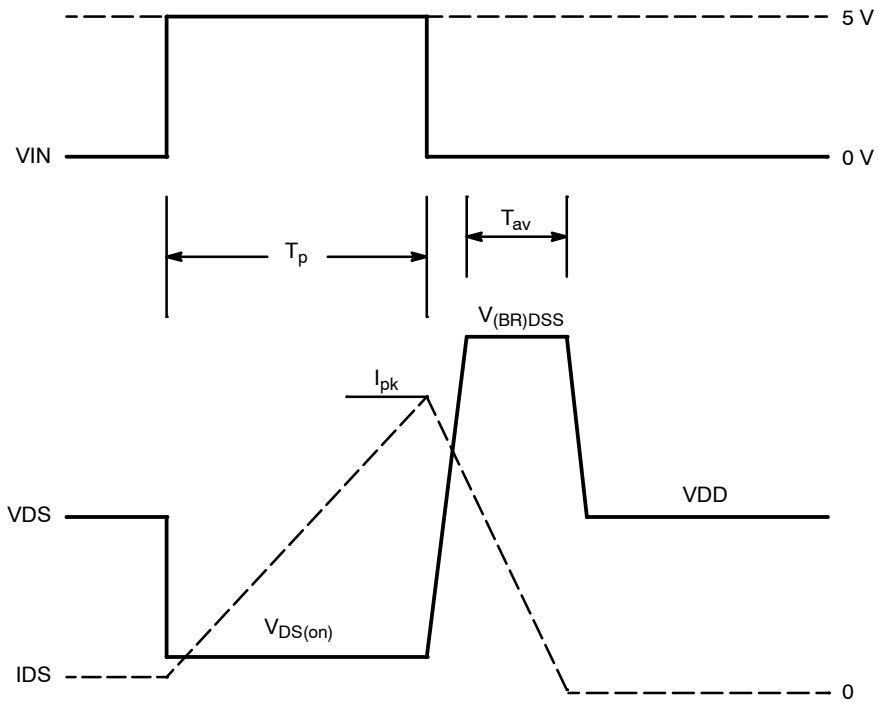
Figure 24. Inductive Load Switching Waveforms

SOIC−8 NB
CASE 751−07
ISSUE AK

DATE 16 FEB 2011

8

1

SCALE 1:1

−X−

A

B

S

−Y−

G

8   5

1   4

⊕ | 0.25 (0.010) Ⓜ | Y | Ⓜ

K

−Z−

C

SEATING PLANE

⌒ | 0.10 (0.004)

H

D

⊕ | 0.25 (0.010)Ⓜ | Z | Y Ⓢ | X Ⓢ

N X 45°

M   J
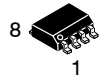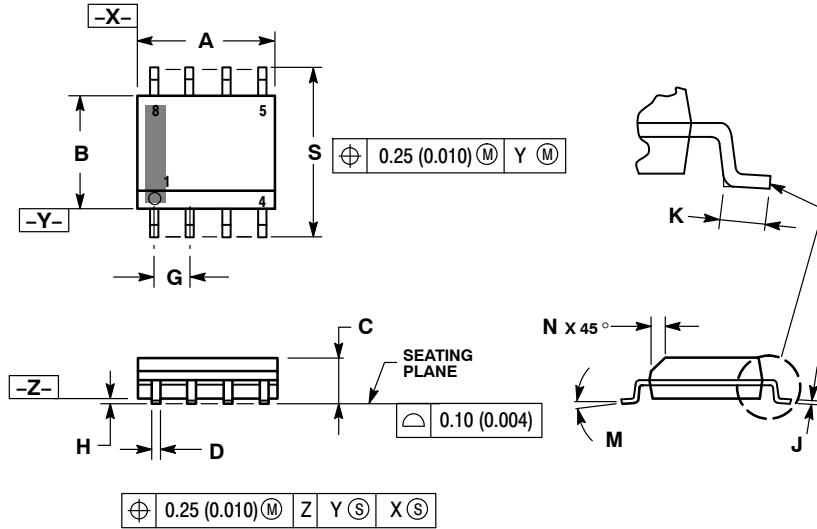
NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
6. 751−01 THRU 751−06 ARE OBSOLETE. NEW STANDARD IS 751−07.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.80	5.00	0.189	0.197
B	3.80	4.00	0.150	0.157
C	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27 BSC		0.050 BSC	
H	0.10	0.25	0.004	0.010
J	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
M	0°	8°	0°	8°
N	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

GENERIC MARKING DIAGRAM*

8   8

XXXXX
ALYWX

XXXXX
ALYWX

1   1

IC   **IC (Pb−Free)**

8   8

XXXXXX
AYWW

XXXXXX
AYWW

1   1

Discrete   **Discrete (Pb−Free)**

XXXXX = Specific Device Code
A = Assembly Location
L = Wafer Lot
Y = Year
W = Work Week
▪ = Pb−Free Package

XXXXXX = Specific Device Code
A = Assembly Location
Y = Year
WW = Work Week
▪ = Pb−Free Package

SOLDERING FOOTPRINT*

1.52
0.060

7.0
0.275

4.0
0.155

0.6
0.024

1.270
0.050

SCALE 6:1   (mm / inches)

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, "G" or microdot "▪", may or may not be present. Some products may not follow the Generic Marking.

*For additional information on our Pb−Free strategy and soldering details, please download the **onsemi** Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

STYLES ON PAGE 2

DOCUMENT NUMBER:	98ASB42564B		
DESCRIPTION:	SOIC−8 NB		**PAGE 1 OF 2**

SOIC−8 NB
CASE 751−07
ISSUE AK

DATE 16 FEB 2011

STYLE 1:
PIN 1. EMITTER
2. COLLECTOR
3. COLLECTOR
4. EMITTER
5. EMITTER
6. BASE
7. BASE
8. EMITTER

STYLE 2:
PIN 1. COLLECTOR, DIE, #1
2. COLLECTOR, #1
3. COLLECTOR, #2
4. COLLECTOR, #2
5. BASE, #2
6. EMITTER, #2
7. BASE, #1
8. EMITTER, #1

STYLE 3:
PIN 1. DRAIN, DIE #1
2. DRAIN, #1
3. DRAIN, #2
4. DRAIN, #2
5. GATE, #2
6. SOURCE, #2
7. GATE, #1
8. SOURCE, #1

STYLE 4:
PIN 1. ANODE
2. ANODE
3. ANODE
4. ANODE
5. ANODE
6. ANODE
7. ANODE
8. COMMON CATHODE

STYLE 5:
PIN 1. DRAIN
2. DRAIN
3. DRAIN
4. DRAIN
5. GATE
6. GATE
7. SOURCE
8. SOURCE

STYLE 6:
PIN 1. SOURCE
2. DRAIN
3. DRAIN
4. SOURCE
5. SOURCE
6. GATE
7. GATE
8. SOURCE

STYLE 7:
PIN 1. INPUT
2. EXTERNAL BYPASS
3. THIRD STAGE SOURCE
4. GROUND
5. DRAIN
6. GATE 3
7. SECOND STAGE Vd
8. FIRST STAGE Vd

STYLE 8:
PIN 1. COLLECTOR, DIE #1
2. BASE, #1
3. BASE, #2
4. COLLECTOR, #2
5. COLLECTOR, #2
6. EMITTER, #2
7. EMITTER, #1
8. COLLECTOR, #1

STYLE 9:
PIN 1. EMITTER, COMMON
2. COLLECTOR, DIE #1
3. COLLECTOR, DIE #2
4. EMITTER, COMMON
5. EMITTER, COMMON
6. BASE, DIE #2
7. BASE, DIE #1
8. EMITTER, COMMON

STYLE 10:
PIN 1. GROUND
2. BIAS 1
3. OUTPUT
4. GROUND
5. GROUND
6. BIAS 2
7. INPUT
8. GROUND

STYLE 11:
PIN 1. SOURCE 1
2. GATE 1
3. SOURCE 2
4. GATE 2
5. DRAIN 2
6. DRAIN 2
7. DRAIN 1
8. DRAIN 1

STYLE 12:
PIN 1. SOURCE
2. SOURCE
3. SOURCE
4. GATE
5. DRAIN
6. DRAIN
7. DRAIN
8. DRAIN

STYLE 13:
PIN 1. N.C.
2. SOURCE
3. SOURCE
4. GATE
5. DRAIN
6. DRAIN
7. DRAIN
8. DRAIN

STYLE 14:
PIN 1. N−SOURCE
2. N−GATE
3. P−SOURCE
4. P−GATE
5. P−DRAIN
6. P−DRAIN
7. N−DRAIN
8. N−DRAIN

STYLE 15:
PIN 1. ANODE 1
2. ANODE 1
3. ANODE 1
4. ANODE 1
5. CATHODE, COMMON
6. CATHODE, COMMON
7. CATHODE, COMMON
8. CATHODE, COMMON

STYLE 16:
PIN 1. EMITTER, DIE #1
2. BASE, DIE #1
3. EMITTER, DIE #2
4. BASE, DIE #2
5. COLLECTOR, DIE #2
6. COLLECTOR, DIE #2
7. COLLECTOR, DIE #1
8. COLLECTOR, DIE #1

STYLE 17:
PIN 1. VCC
2. V2OUT
3. V1OUT
4. TXE
5. RXE
6. VEE
7. GND
8. ACC

STYLE 18:
PIN 1. ANODE
2. ANODE
3. SOURCE
4. GATE
5. DRAIN
6. DRAIN
7. CATHODE
8. CATHODE

STYLE 19:
PIN 1. SOURCE 1
2. GATE 1
3. SOURCE 2
4. GATE 2
5. DRAIN 2
6. MIRROR 2
7. DRAIN 1
8. MIRROR 1

STYLE 20:
PIN 1. SOURCE (N)
2. GATE (N)
3. SOURCE (P)
4. GATE (P)
5. DRAIN
6. DRAIN
7. DRAIN
8. DRAIN

STYLE 21:
PIN 1. CATHODE 1
2. CATHODE 2
3. CATHODE 3
4. CATHODE 4
5. CATHODE 5
6. COMMON ANODE
7. COMMON ANODE
8. CATHODE 6

STYLE 22:
PIN 1. I/O LINE 1
2. COMMON CATHODE/VCC
3. COMMON CATHODE/VCC
4. I/O LINE 3
5. COMMON ANODE/GND
6. I/O LINE 4
7. I/O LINE 5
8. COMMON ANODE/GND

STYLE 23:
PIN 1. LINE 1 IN
2. COMMON ANODE/GND
3. COMMON ANODE/GND
4. LINE 2 IN
5. LINE 2 OUT
6. COMMON ANODE/GND
7. COMMON ANODE/GND
8. LINE 1 OUT

STYLE 24:
PIN 1. BASE
2. EMITTER
3. COLLECTOR/ANODE
4. COLLECTOR/ANODE
5. CATHODE
6. CATHODE
7. COLLECTOR/ANODE
8. COLLECTOR/ANODE

STYLE 25:
PIN 1. VIN
2. N/C
3. REXT
4. GND
5. IOUT
6. IOUT
7. IOUT
8. IOUT

STYLE 26:
PIN 1. GND
2. dv/dt
3. ENABLE
4. ILIMIT
5. SOURCE
6. SOURCE
7. SOURCE
8. VCC

STYLE 27:
PIN 1. ILIMIT
2. OVLO
3. UVLO
4. INPUT+
5. SOURCE
6. SOURCE
7. SOURCE
8. DRAIN

STYLE 28:
PIN 1. SW_TO_GND
2. DASIC_OFF
3. DASIC_SW_DET
4. GND
5. V_MON
6. VBULK
7. VBULK
8. VIN

STYLE 29:
PIN 1. BASE, DIE #1
2. EMITTER, #1
3. BASE, #2
4. EMITTER, #2
5. COLLECTOR, #2
6. COLLECTOR, #2
7. COLLECTOR, #1
8. COLLECTOR, #1

STYLE 30:
PIN 1. DRAIN 1
2. DRAIN 1
3. GATE 2
4. SOURCE 2
5. SOURCE 1/DRAIN 2
6. SOURCE 1/DRAIN 2
7. SOURCE 1/DRAIN 2
8. GATE 1

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ADDITIONAL INFORMATION

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